## [AMDp2]Active-Matrix Devices Thu. Nov 28, 2019 2:30 PM - 5:00 PM Main Hall (1F)

## 2:30 PM - 5:00 PM

## [AMDp2-11]Analysis of Horizontal-Mura Caused by Reset's Abnormal Delay of GOA Output

\*Xinmao Qiu<sup>1</sup>, Yao Liu<sup>1</sup>, Hongjiang Wu<sup>1</sup>, Hongtao Lin<sup>1</sup>, Baoqiang Wang<sup>1</sup>, Wenchao Wang<sup>1</sup>, Yaochao Lv<sup>1</sup>, Guichun Hong<sup>1</sup>, Min Zhou<sup>1</sup>, Zuwen Liu<sup>1</sup> (1. Fuzhou BOE Optoelectronics Technology Co., Ltd (China)) Keywords:Gate Driver on Array, Horizontal-Mura, Leakage Current, Array Design

A rare failure named Horizontal-Mura Caused by Reset's abnormal Delay of GOA Output is studied systemically. By increasing frame frequency, changing TFT size ratio and increasing channel Length, the leakage current of voltage Gout's Gate (PU) can be reduced, and Mura phenomenon can be significantly alleviated.